

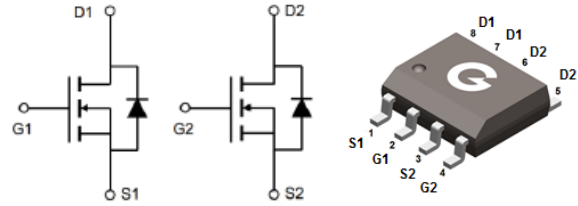
Features

- Lower $R_{DS(on)}$
- Good stability and uniformity

HF

Mechanical Data

- Case: SOP-8
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208



SOP-8

Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
GBLN3303-S8	SOP-8	4000 pcs / Tape & Reel	GBLN3303

Maximum Ratings (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V_{DSS}	30	V
Gate-to-Source Voltage	V_{GSS}	± 20	V
Continuous Drain Current ($T_C = 25^\circ\text{C}$)	I_D	10	A
Continuous Drain Current ($T_A = 25^\circ\text{C}$) ^{*1}		6	A
Continuous Drain Current ($T_A = 100^\circ\text{C}$) ^{*1}		3.8	A
Pulsed Drain Current ($t_p = 10\mu\text{s}$, $T_A = 25^\circ\text{C}$)	I_{DM}	36	A
Single Pulse Avalanche Energy ^{*4}	E_{AS}	40	mJ
Power Dissipation ($T_A = 25^\circ\text{C}$) ^{*1}	P_D	2	W
Operating Junction Temperature Range	T_J	-55 ~ +150	$^\circ\text{C}$
Storage Temperature Range	T_{STG}	-55 ~ +150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	-	20	25	$^\circ\text{C/W}$
Thermal Resistance Junction-to-Air ^{*1}	$R_{\theta JA}$	-	55	62.5	$^\circ\text{C/W}$
Thermal Resistance Junction-to-Air ^{*2}		-	70	80	$^\circ\text{C/W}$

Electrical Characteristics (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
Static Characteristics						
V_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24V, V_{GS} = 0V$	-	-	1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	± 100	nA
On Characteristics						
$R_{DS(ON)}$	Drain-Source On-resistance ^{*3}	$V_{GS} = 10V, I_D = 6.3A$	-	18	30	m Ω
		$V_{GS} = 4.5V, I_D = 4.8A$	-	25	45	m Ω
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	1.6	2.5	V
R_G	Gate Resistance	$V_{GS} = 0V, f = 1MHz$	-	8.4	-	Ω
Dynamic Characteristics						
C_{ISS}	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 15V$ $f = 1.0MHz$	-	492	-	pF
C_{OSS}	Output Capacitance		-	64	-	
C_{RSS}	Reverse Transfer Capacitance		-	59	-	
Switching Characteristics						
$t_{d(ON)}$	Turn-on Delay Time ^{*5}	$V_{DD} = 20V, V_{GS} = 10V$ $R_G = 3\Omega, R_L = 1\Omega$ $I_D = 8A$	-	10	-	ns
t_r	Turn-on Rise Time ^{*5}		-	12	-	
$t_{d(OFF)}$	Turn-Off Delay Time ^{*5}		-	32	-	
t_f	Turn-Off Fall Time ^{*5}		-	8	-	
Q_G	Total Gate-Charge	$V_{DD} = 15V$	-	14.6	-	nC
Q_{GS}	Gate to Source Charge	$V_{GS} = 10V$	-	2.4	-	
Q_{GD}	Gate to Drain (Miller) Charge	$I_D = 5.8A$	-	2.9	-	
Source-Drain Diode Characteristics						
V_{SD}	Diode Forward Voltage ^{*3}	$I_{SD} = 1A, V_{GS} = 0V$	-	0.76	1.2	V
t_{rr}	Reverse Recovery Time	$I_F = 5A, V_{GS} = 0V$ $dI_F/dt = 100A/\mu s$	-	75	-	ns
Q_{rr}	Reverse Recovery Charge		-	36	-	nC

Notes:

- The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, $t \leq 10s$
- The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, steady state
- The data tested by pulsed, pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- The E_{AS} data shows Max. rating. The test condition is $V_{DD} = 25V, V_{GS} = 10V, L = 10mH$
- Guaranteed by design, not subject to production

Ratings and Characteristics Curves (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

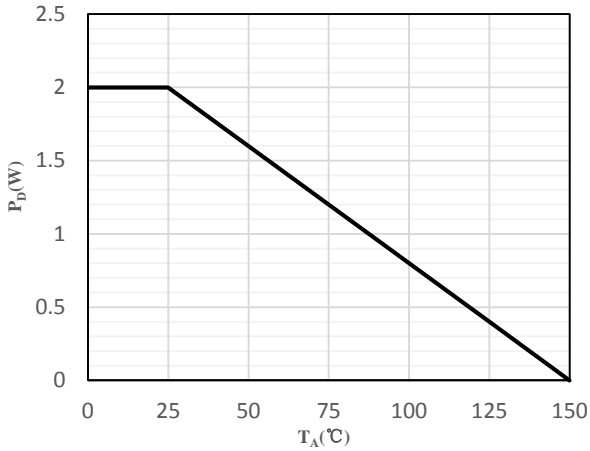


Fig 1 Power Dissipation

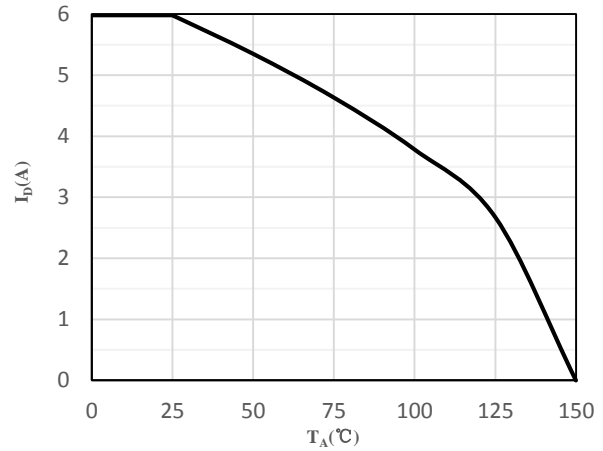


Fig 2 Drain Current

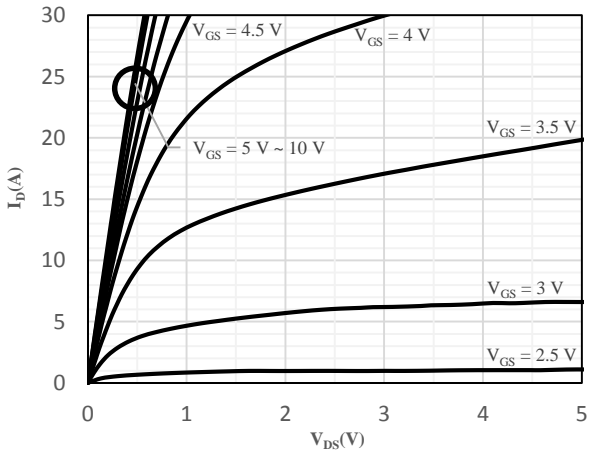


Fig 3 Typical Output Characteristics

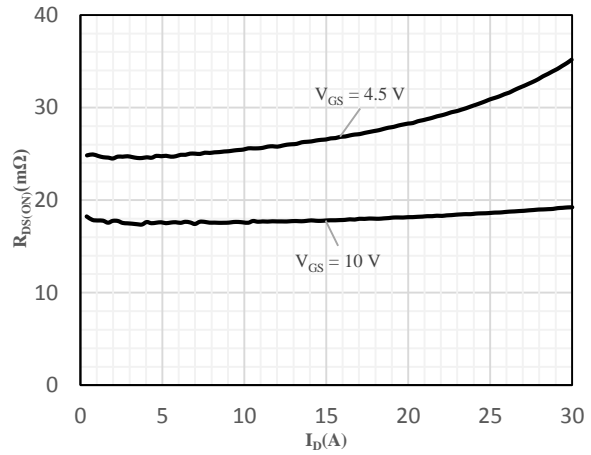


Fig 4 On-Resistance vs. Drain Current and Gate Voltage

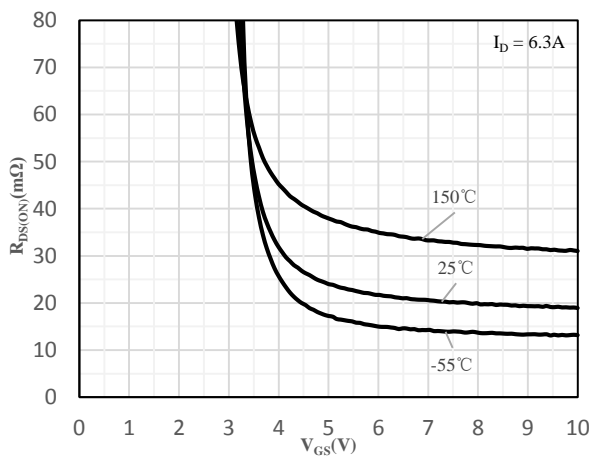


Fig 5 On-Resistance vs. Gate-Source Voltage

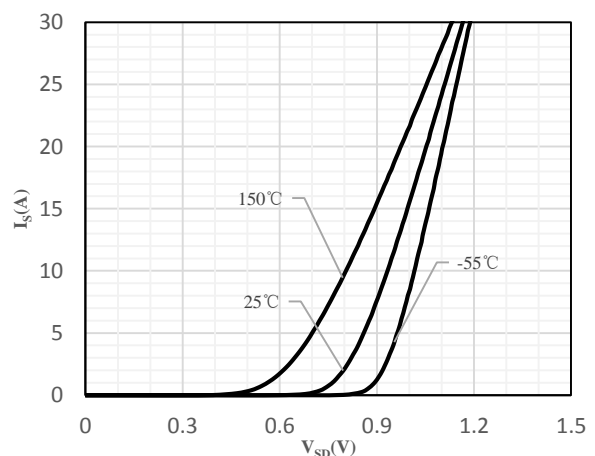


Fig 6 Body-Diode Characteristics

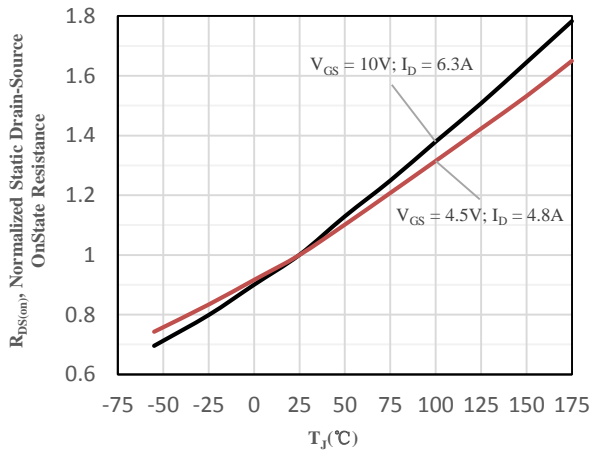


Fig 7 Normalized On-Resistance vs. Junction Temperature

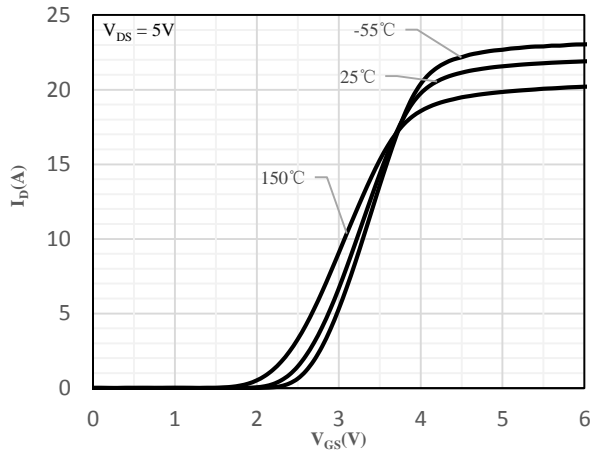


Fig 8 Transfer Characteristics

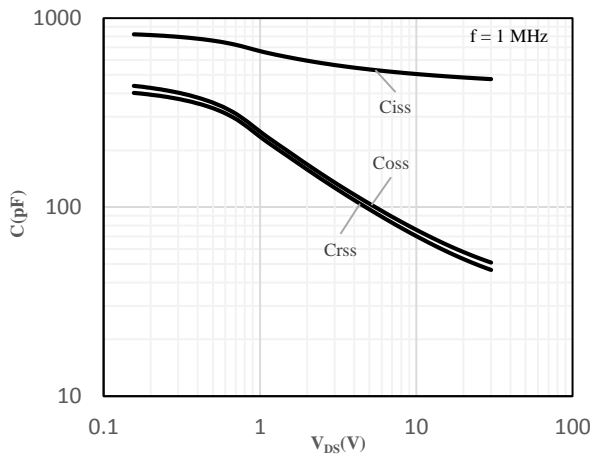


Fig 9 Capacitance Characteristics

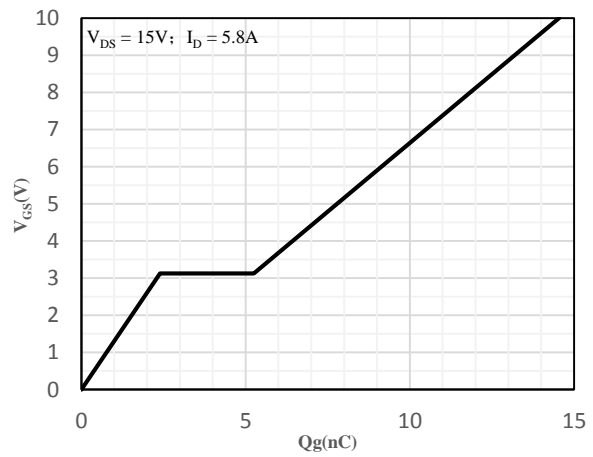


Fig 10 Gate-Charge Characteristics

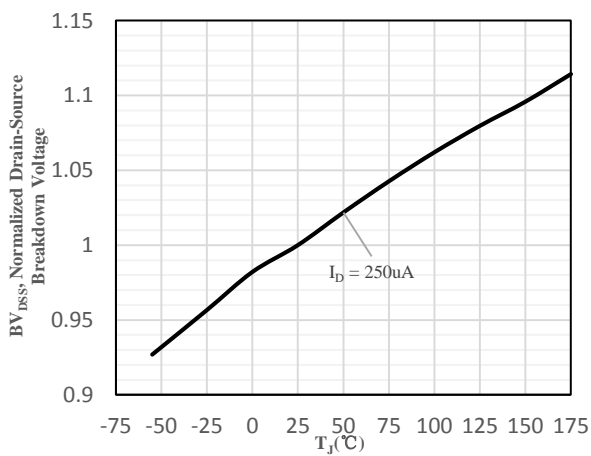


Fig 11 Normalized Breakdown Voltage vs. Junction Temperature

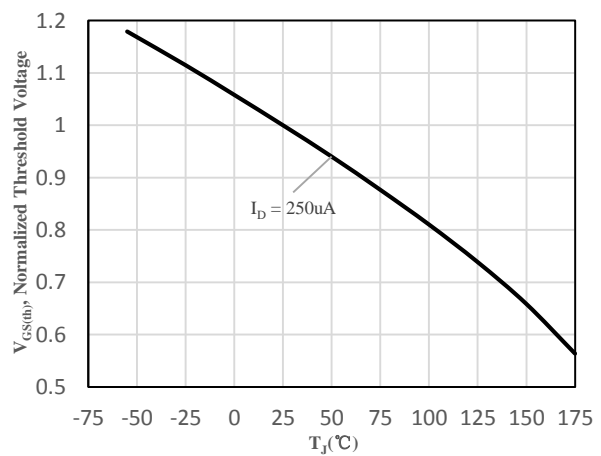


Fig 12 Normalized $V_{GS(th)}$ vs. Junction Temperature

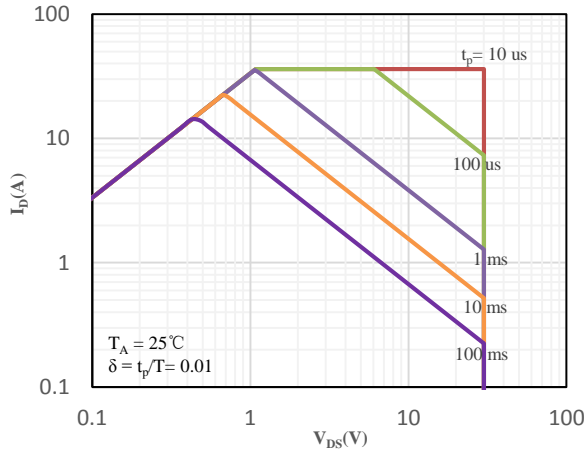


Fig 13 Safe Operation Area

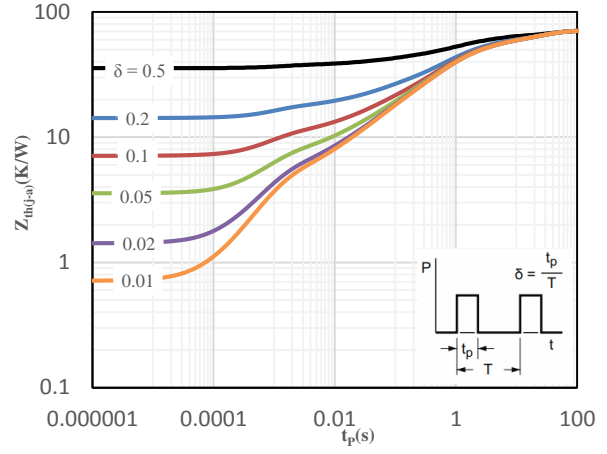
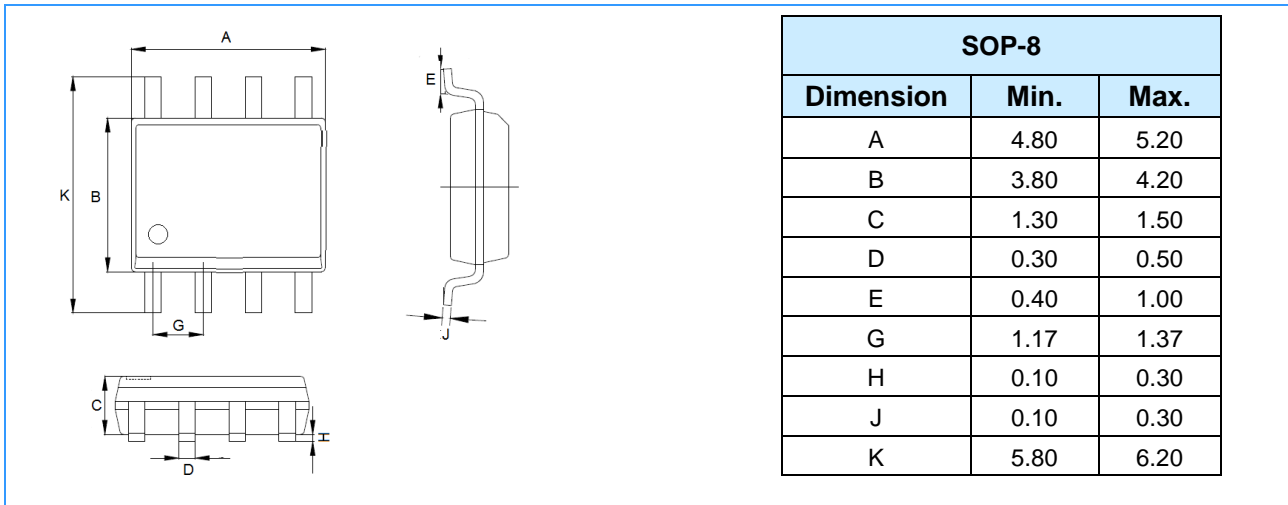
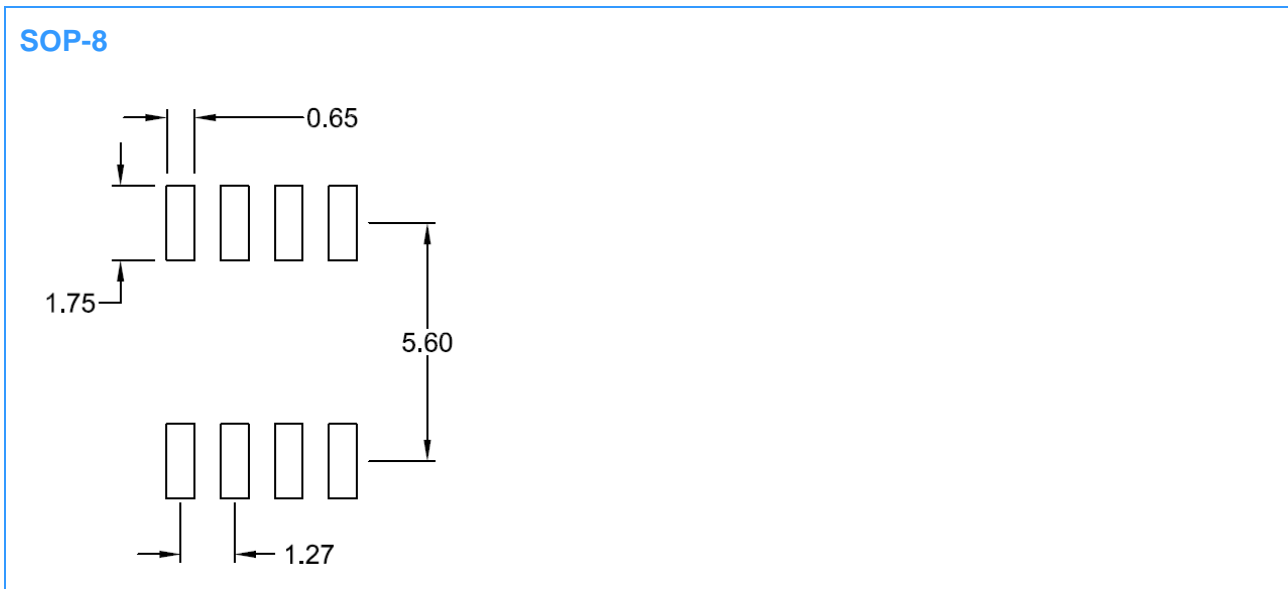


Fig 14 Maximum transient thermal impedance

Package Outline Dimensions (Unit: mm)



Mounting Pad Layout (Unit: mm)



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